UNITED STATES SECURITIES AND EXCHANGE COMMISSION Washington, D.C. 20549

FORM 8-K

CURRENT REPORT

Pursuant to Section 13 or 15(d) of the Securities Exchange Act of 1934

Date of Report

(Date of earliest event reported): January 30, 2024

Aeluma, Inc.

(Exact name of registrant as specified in its charter)

000-56218 (Commission File Number) 85-2807351 (IRS Employer Identification No.)

Delaware (State or other jurisdiction of incorporation)

27 Castilian Drive

Goleta, California

(Address of principal executive offices)

93117

(Zip Code)

805-351-2707

(Registrant's telephone number, including area code)

Check the appropriate box below if the Form 8-K filing is intended to simultaneously satisfy the filing obligation of the registrant under any of the following provisions:

□ Written communications pursuant to Rule 425 under the Securities Act (17 CFR 230.425)

□ Soliciting material pursuant to Rule 14a-12 under the Exchange Act (17 CFR 240.14a-12)

□ Pre-commencement communications pursuant to Rule 14d-2(b) under the Exchange Act (17 CFR 240.14d-2(b))

□ Pre-commencement communications pursuant to Rule 13e-4(c) under the Exchange Act (17 CFR 240.13e-4(c))

Securities registered pursuant to Section 12(b) of the Act: none.

Indicate by check mark whether the registrant is an emerging growth company as defined in Rule 405 of the Securities Act of 1933 (§230.405 of this chapter) or Rule 12b-2 of the Securities Exchange Act of 1934 (§240.12b-2 of this chapter).

Emerging growth company 🗵

If an emerging growth company, indicate by check mark if the registrant has elected not to use the extended transition period for complying with any new or revised financial accounting standards provided pursuant to Section 13(a) of the Exchange Act.

Item 8.01 Other Events.

We are filing this report to disclose a Company PowerPoint presentation, a Company flier, and three product offering brochures. The presentation, flier, and brochures are all furnished as exhibits to this Current Report on Form 8-K.

Neither this report nor the exhibits attached hereto constitute an offer to sell, or the solicitation of an offer to buy our securities, nor shall there be any sale of our securities in any state or jurisdiction in which such offer, solicitation or sale would be unlawful prior to the registration or qualification under the securities laws of any such state or jurisdiction.

Item 9.01 Financial Statements and Exhibits.

(d) Exhibits.

Exhibit	
Number	Exhibit
99.1	PowerPoint Presentation
99.2	Company Flier
99.3	Product Offering Brochure #1
99.4	Product Offering Brochure #2
99.5	Product Offering Brochure #3
104	Cover Page Interactive Data File (embedded within the Inline XBRL document)

0211-

Pursuant to the requirements of the Securities Exchange Act of 1934, the registrant has duly caused this report to be signed on its behalf by the undersigned hereunto duly authorized.

AELUMA, INC.

Date: January 30, 2024

By: /s/ Jonathan Klamkin

Jonathan Klamkin President, Chief Executive Officer and Director





Large-Wafer Heterogeneously Integrated InGaAs Photodetector Sensors

Matthew Dummer, Jonathan Klamkin, Bei Shi, Bowen Song, Simone S. Brunelli, Michael McGivney, Douglas Oakley, Daniel Renner

> Paper 12880-18 January 30, 2024



Outline

- Introduction to Aeluma
- Background on InGaAs detectors and scaling limitations
- Aeluma's scalable large-diameter wafer platform
- Detector array performance results
- Comparison to other detector technologies
- Summary of product and technology offerings
- Conclusions



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At a Glance

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Aeluma, Inc. (OTCQB: ALMU)

A transformative semiconductor chip company High Performance Semiconductors that Scale

Headquarters: Goleta/Santa Barbara, California

<u>Markets</u>: Automotive LiDAR, Mobile, AR/VR, Communication, Defense & Aerospace, AI

Team: ~15 people

Expertise: Compound semiconductors, heteroepitaxy, photonic integrated circuits, silicon photonics, lasers, detectors, volume manufacturing

Intellectual Property: "25 issued and pending patents, trade secrets

Background on InGaAs Detectors

High Performance Detectors for Active and Passive Imaging



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InGaAs: Indium Gallium Arsenide; LiDAR: Light detection and ranging; FPA: Focal plane array. Note: Outcomes cannot be guaranteed. Sources of images: https://www.flic.com/support/productSs/wir-ingaas-fpa; https://www.bhphotovideo.com; https://www.wardsauto.com/vehicles/lidar-house-battery-production-voi https://wir-icom/biointhiticom/support/productSs/mir-ingaas-fpa; https://www.bhphotovideo.com; https://www.wardsauto.com/vehicles/lidar-house-battery-production-voi https://wir-icom/support/productSs/mir-ingaas-fpa; https://www.bhphotovideo.com; https://www.wardsauto.com/vehicles/lidar-house-battery-production-voi

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The Aeluma Approach to Photonics Manufacturing



High Performance Technology with Large-Diameter Wafer Manufacturing



Aeluma's Technology Breakthrough



Scalable, Cost-Effective Manufacturing Enabled by Cutting-Edge Intellectual Property



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Note: Outcomes cannot be guaranteed.

Aeluma's Cost-Effective Scalable Manufacturing



Large-Diameter Wafer Capability

- Commercial 12-inch state-of-the-art deposition tool
- Set up for cassette (FOUP) loading production
- One of only a few such tools worldwide
- Extensive patent protection and trade secrets



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Aeluma's Cost-Effective Scalable Manufacturing

Large-Diameter Wafer Capability

InP-on-Silicon Wafer



Photoluminescence Mapping Measurements



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Wafer-Scale Integration and 3D Packaging



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Silicon Manufacturing Environment Enables Wafer-Scale Packaging



Manufacturing for a Mass Market

Aeluma's Large-Diameter Manufacturing Economies of Scale



Photodetector Array Performance

Exemplary 128 X 32 InGaAs Array on 8-inch Platform







Very low dark current demonstrated along with high array yield

Dark Current Temperature Dependence







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All measurements performed at -5V bias

Aeluma Outperforms the Competition



Technology Comparison



Summary of Product/Technology Offerings



Detector Arrays

Custom Detector Arrays

- Low dark current photodetector arrays manufactured with large-diameter substrate platform
- · Pixel and array size customizable
- Typical array sizes: 128 X 32, 256 X 128, 640 X 512
- Delivered as PDA chips or with ROICs
- · FPA assembly available
- Small test arrays (ex. 8 X 8) available for eval./qual.





Examples shown are 256 X 128 arrays

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Focal Plane Array Assembly



Applicable markets include automotive, mobile, AR/VR, defense & aerospace, industrial and logistics, and security

Summary of Product/Technology Offerings



TO Package

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Large-Area InGaAs Detectors

High sensitivity, low dark current and high speed detectors for SWIR and XSWIR

- Typical Photosensitive Diameter (D): 0.25 to 5.0mm
- Typical Operating Wavelength (λ): 0.95 to 1.55 μ m)
- · Device: PIN, APD or SPAD
- Format: Bare die or mounted in TO package



Bare Die



Applicable markets include automotive, mobile, AR/VR, defense & aerospace, industrial and logistics, gas sensing, instrumentation, and security

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Summary of Product/Technology Offerings



Large-Scale Detectors for

Wafer-Scale Integration

Lasers for Silicon Photonics

Integration of guantum dot lasers and other

group III-V active devices in Silicon Photonics

Manufacturing detectors on

the same substrate size as

read-out ICs enables wafer-

scale integration to improve

Grating Low-less Edge

performance, increase functionality, and reduce cost.

PDA Wafer

Heterogeneous Integration Platform



Aeluma's proprietary heterogeneous integration platform integrates highperformance compound semiconductors (ex. GaAs, InP, GaSb) on large-diameter substrates including up to 12-inch Silicon.

This technology has the potential to scale, reduce cost, and increase yield, all of which are critical for emerging and massmarket applications.

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Summary of Offerings

High Quality Templates



High-quality GaAs, InP, and GaSb templates grown on up to 12-inch Silicon substrates for scaling highperformance technologies to larger wafer sizes.

Monolithic Integration by Selective Growth



Selective growth enables CMOS process integration and may be applied to Silicon Photonics, III-V electronics integrated with Silicon CMOS, integration of InGaAs detectors with CMOS read-out ICs, and more.

Applicable markets include automotive, mobile, AR/VR, defense & aerospace, quantum computing, AI, and communication

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Silicon Photonics and Laser Integration

Aeluma's Technology Can Enable Process Integration



Silicon Photonics Applications

High-Performance Computing and Data Centers

AI and Photonic Computing

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Lasers for Silicon Photonics

Integration of quantum dot lasers and other group III-V active devices in Silicon Photonics

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Outcomes cannot be guaranteed. Sources of images: https://venturebeat.com; https://spie.org/news/photonics-focus

Aiming to Service a Broad Market



High-Performance Semiconductors for Sensing and Communications



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- Large-diameter wafer platform capable of scaling InGaAs detector arrays and other technologies for consumer markets including automotive and mobile
- Demonstrated very low dark current detector arrays on 8-inch wafer platform with excellent pixel yield, wafer uniformity, and high-temperature performance
- Developed selective growth processes for monolithic integration on Silicon CMOS •
- Technologies available include detector arrays, large-area detectors, and • heterogenous integration platform

Visit Aeluma at Booth 5143

info@aeluma.com | www.aeluma.com

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The Aeluma Semiconductor Manufacturing Approach

High-Performance Semiconductors with Large-Diameter Substrates





Automotive LiDAR for Driving Safety and Autonomy

Manufacturing for a Mass Market without Sacrificing Performance



Aeluma Competitive Advantage



Aeluma combines proven, high-performance InGaAs with scalable manufacturing on large-diameter substrates to overcome the cost-performance tradeoff.

Outcomes cannot be guaranteed. Source of car/sensor figure: https://www.eetimes.com/why-sensor-technology-is-the-key-to-autonomous-vehicles/ LIDAR: Light Detection and Ranging

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About Aeluma

Aeluma develops novel optoelectronics for sensing and communication applications. Aeluma has pioneered a technique to manufacture semiconductor chips using high-performance compound semiconductor materials on large-diameter substrates that are commonly used for mass-market microelectronics. The technology has the potential to enhance performance and scale manufacturing, both of which are critical for emerging applications. Aeluma is developing a streamlined business model from its headquarters in Santa Barbara, California that has a state-of-the-art manufacturing cleanroom. Its transformative semiconductor chip technology may impact a variety of markets including automotive LiDAR, mobile, defense & aerospace, AR/VR, AI, quantum, and communication.

Aeluma differentiates itself with unique semiconductor manufacturing capability, proprietary technology, the ability to perform rapid prototyping, and a broad set of product offerings.

For more information: info@aeluma.com

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Sensing Reimagined[™]



Large Area InGaAs Detectors



High sensitivity, low dark current and high speed detectors for SWIR and XSWIR

- Typical Photosensitive Diameter (D): 0.25 to 5.0mm
- Typical Operating Wavelength (λ): 0.95 to 1.55μm)
- Device: PIN, APD or SPAD
- · Format: Bare die or mounted in TO package

Performance Specifications for λ = 1.064 μ m, D = 1.0mm InGaAs PIN

Rectar States	500000	226200		Value	Value	
Parameter	Symbol	Condition	Min.	Тур.	Max.	Unit
Spectral Response Range	λ_{R}		0.95	1.064	1.15	μm
Peak Sensitivity Wavelength	λ _P		× .	1.064		μm
Quantum Efficiency	η	$\lambda = \lambda_P$	0.6	0.75	0.9	-
Responsivity	R	$\lambda = \lambda_P$	0.52	0.64	0.77	A/W
Dark Current	ID	V = -5V	×	0.2	-	nA
Terminal Capacitance	CT	V = -5V f = 2MHz	-	125	-	pF





TO Package



Outcomes cannot be guaranteed. Specifications for operating temperature of 25°C.

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Applications and Markets







High-performance, large-area detectors for imaging, sensing and communication applications

Applicable markets include automotive, mobile, AR/VR, defense & aerospace, industrial and logistics, gas sensing, instrumentation, and security

Advantages of Aeluma Large-Scale Manufacturing





- Highly automated manufacturing to produce many chips per wafer at high yield
- Greater than 10-fold reduction in manufacturing cost for mass-market applications
- Wafer-scale integration for volume production, performance improvement, and lower cost

Benefits of Large-Scale Integration



Manufacturing on large-diameter substrates

- Low cost
- Larger area detectors
- High yield
- High reliability
- Scalability
- Large volumes

Aeluma's large-diameter wafer manufacturing platform is ideally suited for scaling high-performance, large-area detectors for mass markets

Outcomes cannot be guaranteed

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Custom Detector Arrays





Examples shown are 256 X 128 arrays

Constituenting.	Value					
Specification	Min.	Тур.	Max.	Unit		
Pixel Pitch	5	10	-	μm		
Rows	1		-			
Columns	1	-	-			
Peak Sensitivity Wavelength	0.95		1.55	μm		
Detector Type	PIN • APD • SPAD					
Configuration	Common Anode • Common Cathode					

Custom Array Specifications

Performance, Formats and Features

- Low dark current photodetector arrays manufactured with large-diameter substrate platform
- · Pixel and array size customizable
- Typical array sizes: 128 X 32, 256 X 128, 640 X 512
- Reliability performance exceeds generic Telcordia GR-468 optoelectronics standard
- · Delivered as PDA chips or with ROICs
- · FPA assembly available
- Small test arrays (ex. 8 X 8) available for eval./qual.

Outcomes cannot be guaranteed. PDA: Photodetector Array, ROIC: Read-out Integrated Circuit; FPA: Focal Plane Array



Focal Plane Array Assembly

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Focal Plane Arrays



Passive Imaging

LiDAR Sensing





High-performance photodetector arrays used in focal plane array applications, passive imaging, and active LiDAR sensing

Applicable markets include automotive, mobile, AR/VR, defense & aerospace, industrial and logistics, and security

Advantages of Aeluma Large-Scale Manufacturing





Sensing Reimagined[™]

- Highly automated manufacturing to produce many chips per wafer at high yield
- Greater than 10-fold reduction in manufacturing cost for mass-market applications
- Wafer-scale integration for volume production, performance improvement, and lower cost

Benefits of Large-Scale Integration

Chip-to-chip integration



Traditional chip-to-chip / die-to-die hybridization is low throughput and high cost.

Indium bump technology poses challenges on integration and packaging, and limits the minimum pixel size and maximum array size.

Wafer-scale Integration



Wafer-scale integration, including die-to-wafer and wafer-to-wafer, enables high throughput and low cost.

Copper-based interconnects improve performance.

Smaller pixel size and larger format arrays are possible with CMOS interconnects and 3D stacking.

Sources of images: https://www.firr.com/support/products/swir-ingaas-fpa/, https://www.bhphotovideo.com, https://ouster.com/biog/mhttps://www.foresightauto.com/themai-cameras-solve-autonomous-trucks-dust-problem/akeintersections-safer-ttb/; www.digikey.com & Rogalski, Optical Engineering, 42(12), 2003; https://www.allaboutcircuits-com/mews/moores-law-xperinew-die-to-water-bonding-technology-ic-package/, E. Charbort, et al., KZCS, 2018. Outcomes cannot be guaranteed.

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Heterogeneous Integration Platform



Aeluma's proprietary heterogeneous integration platform integrates highperformance compound semiconductors (ex. GaAs, InP, GaSb) on large-diameter substrates including up to 12-inch Silicon.

This technology has the potential to scale, reduce cost, and increase yield, all of which are critical for emerging and mass-market applications.

Summary of Offerings

High Quality Templates



Aelun

High-quality GaAs, InP, and GaSb templates grown on up to 12-inch Silicon substrates for scaling highperformance technologies to larger wafer sizes.

Monolithic Integration by Selective Growth



Selective growth enables CMOS process integration and may be applied to Silicon Photonics, III-V electronics integrated with Silicon CMOS, integration of InGaAs detectors with CMOS read-out ICs, and more.

Large-Scale Detectors for Wafer-Scale Integration



Manufacturing detectors on the same substrate size as read-out ICs enables waferscale integration to improve performance, increase functionality, and reduce cost.

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Lasers for Silicon Photonics



Integration of quantum dot lasers and other group III-V active devices in Silicon Photonics

Outcomes cannot be guaranteed.

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Applications and Markets





High-performance compound semiconductor devices integrated in large-scale platforms including Silicon CMOS

Applicable markets include automotive, mobile, AR/VR, defense & aerospace, quantum computing, AI, and communication

Advantages of Aeluma Large-Scale Manufacturing





- Highly automated manufacturing to produce many chips per wafer at high yield
- Greater than 10-fold reduction in manufacturing cost for mass-market applications
- Wafer-scale integration for volume production, performance improvement, and lower cost

Benefits of Large-Scale Integration



Manufacturing on large-diameter substrates

- Low cost
- High yield
- High reliability
- Scalability
- Large volumes

Aeluma's large-diameter wafer manufacturing platform is ideally suited for scaling high-performance compound semiconductor devices for mass markets

Outcomes cannot be guaranteed

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